

June 2000

# FQA34N20L

## 200V LOGIC N-Channel MOSFET

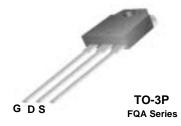
### **General Description**

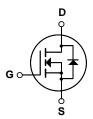
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters, switch mode power supply, motor control.

#### **Features**

- 34A, 200V,  $R_{DS(on)}$  = 0.075 $\Omega$  @V<sub>GS</sub> = 10 V Low gate charge ( typical 55 nC)
- Low Crss (typical 52 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- · Low level gate drive requirement allowing direct opration from logic drivers





# Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		FQA34N20L	Units	
$V_{DSS}$	Drain-Source Voltage		200	V	
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)		34	А	
	- Continuous (T <sub>C</sub> = 100°C)		21	А	
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	136	А	
V <sub>GSS</sub>	Gate-Source Voltage		± 20	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	640	mJ	
I <sub>AR</sub>	Avalanche Current	(Note 1)	34	А	
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	21	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	5.5	V/ns	
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C)		210	W	
	- Derate above 25°C		1.67	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C	
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

# **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.6	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.24		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		40	°C/W

Symbol	Parameter	Test Conditions	•	Min	Тур	Max	Units
Off Cha	aracteristics						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		200			V
ΔBV <sub>DSS</sub> / ΔΤ <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced	to 25°C		0.16		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 200 V, V <sub>GS</sub> = 0 V				1	μΑ
		V <sub>DS</sub> = 160 V, T <sub>C</sub> = 125°C				10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0 V				100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Cha	racteristics						
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		1.0		2.0	V
	Static Drain-Source	$V_{GS} = 10 \text{ V}, I_D = 17 \text{ A}$ $V_{GS} = 5 \text{ V}, I_D = 17 \text{ A}$			0.057	0.075	Ω
	On-Resistance				0.060	0.080	52
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 30 \text{ V}, I_{D} = 17 \text{ A}$	(Note 4)		42		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0  MHz			3000 400 52	3900 520 67	pF pF pF
Switchi	ing Characteristics						<u> </u>
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 100 \text{ V}, I_{D} = 34 \text{ A},$ $R_{G} = 25 \Omega$			45	100	ns
t <sub>r</sub>	Turn-On Rise Time				520	1050	ns
t <sub>d(off)</sub>	Turn-Off Delay Time				170	350	ns
t <sub>f</sub>	Turn-Off Fall Time		(Note 4, 5)		370	750	ns
Qg	Total Gate Charge	V <sub>DS</sub> = 160 V, I <sub>D</sub> = 34 A,			55	72	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 5 V (Note 4, 5)			9.9		nC
Q <sub>gd</sub>	Gate-Drain Charge				27		nC
	ource Diode Characteristics a		5				
l <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				34	A	
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode F					136	A
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V, } I_{S} = 34 \text{ A}$				1.5	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_S = 34 \text{ A},$	(NI=4= 4)		205		ns
$Q_{rr}$	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)			1.1		μC

- $\label{eq:Notes:Notes:1} \begin{tabular}{ll} \textbf{Notes:} \\ 1. & \textbf{Repetitive Rating: Pulse width limited by maximum junction temperature} \\ 2. & \textbf{L} = 0.83 \text{mH, } \textbf{I}_{AS} = 34 \text{A, } \textbf{V}_{DD} = 50 \text{V, } \textbf{R}_{G} = 25 \ \Omega, \textbf{Starting } \textbf{T}_{J} = 25 ^{\circ} \textbf{C} \\ 3. & \textbf{I}_{SD} \leq 34 \text{A, } \text{di/dt} \leq 300 \text{A/\mus, } \textbf{V}_{DD} \leq \textbf{BV}_{DSS,} \textbf{Starting } \textbf{T}_{J} = 25 ^{\circ} \textbf{C} \\ 4. & \textbf{Pulse Test: Pulse width} \leq 300 \text{\mus, Duty cycle} \leq 2 \% \\ 5. & \textbf{Essentially independent of operating temperature} \\ \end{tabular}$

# **Typical Characteristics**

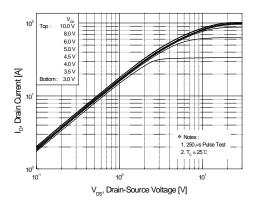


Figure 1. On-Region Characteristics

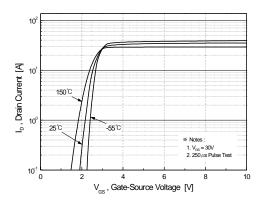


Figure 2. Transfer Characteristics

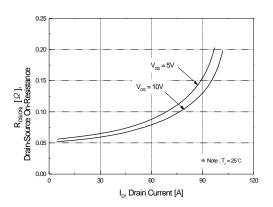


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

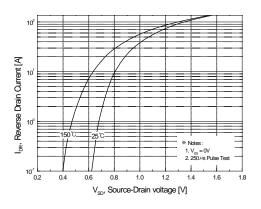


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

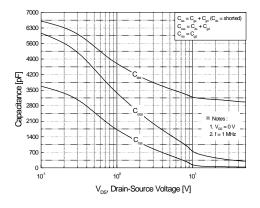


Figure 5. Capacitance Characteristics

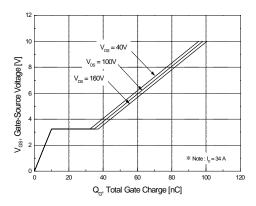
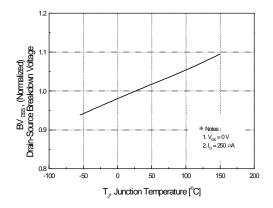


Figure 6. Gate Charge Characteristics

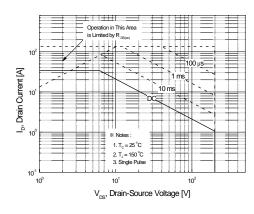
# Typical Characteristics (Continued)



2.5 (Notices: 1.1 V<sub>GS</sub> = 10 V 2.1 × Notes: 1.1 V<sub>GS</sub> = 10 V 2.1 × 17 × 10 V 2.1 × 10 V 2.

Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



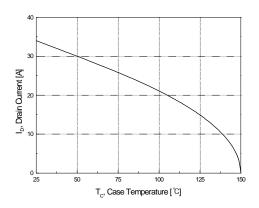


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

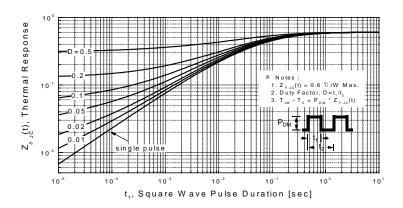
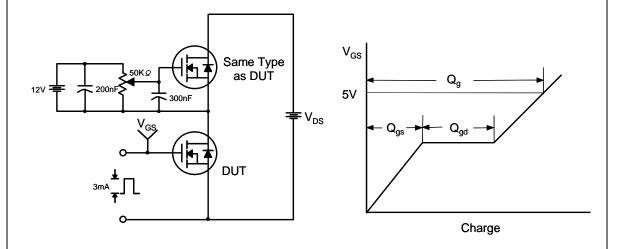


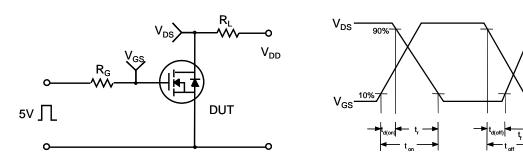
Figure 11. Transient Thermal Response Curve

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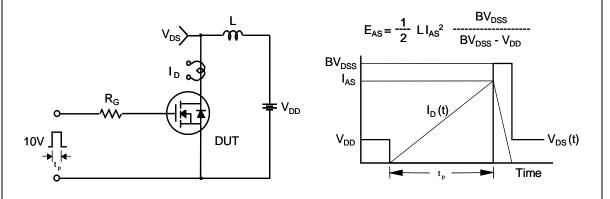
# **Gate Charge Test Circuit & Waveform**



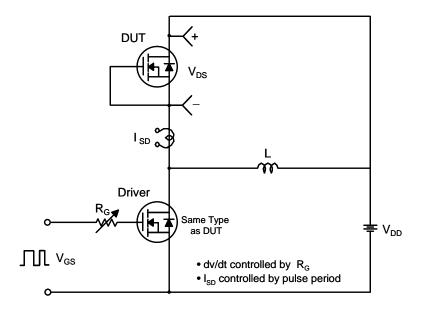
## **Resistive Switching Test Circuit & Waveforms**

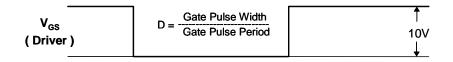


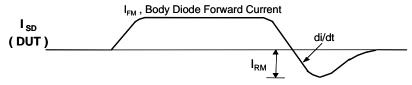
# **Unclamped Inductive Switching Test Circuit & Waveforms**



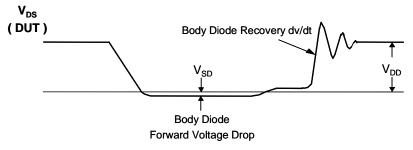
### Peak Diode Recovery dv/dt Test Circuit & Waveforms

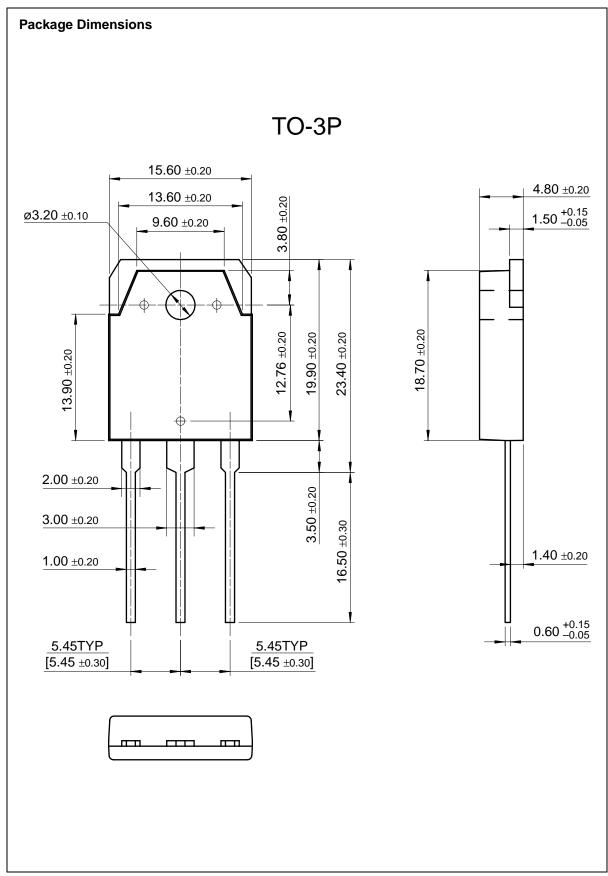






Body Diode Reverse Current





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